


<b>Search Notes</b> 	<b>Application/Control No.</b> 10598807	<b>Applicant(s)/Patent Under Reexamination</b> PAYNE ET AL.
	<b>Examiner</b> HAI V NGUYEN	<b>Art Unit</b> 2618

SEARCHED			
Class	Subclass	Date	Examiner
455	466	03/02/2008	HN

SEARCH NOTES		
Search Notes	Date	Examiner
EAST search (US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB) (see search history printout report)	03/05/2008	HN

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner